

**Automated test pattern generator with constraint solver**

**Viilukas, Taavi; Raik, Jaan** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK neljanda aastakonverentsi artiklite kogumik : 26.-27. novembril 2010, Essu mõis 2010 / lk. 33-36

**Computer-aided testing of students' independent work at overcoming vocabulary difficulties during reading**

Bobyleva, L. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 13-15

**Constraints solving based hierarchical test generation for synchronous sequential circuits = Kitsenduste lahendamisel baseeruv hierarhiline testigeneerimine sünkroonsetele järjestikiskeemidele**

**Viilukas, Taavi** 2012 [https://www.ester.ee/record=b2888278\\*est](https://www.ester.ee/record=b2888278*est)

**Evolutionary approach to test generation for functional BIST**

Skobtsov, Y.A.; Ivanov, D.E.; Skobtsov, V.Y.; **Ubar, Raimund-Johannes; Raik, Jaan** Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. 151-155 : ill [https://artiklid.elnet.ee/record=b1018764\\*est](https://artiklid.elnet.ee/record=b1018764*est)

**20 aastat maailma testiteaduse tippkonkurents**

**Ubar, Raimund-Johannes** Mente et Manu 2015 / lk. 12-13 : fot [https://artiklid.elnet.ee/record=b2749536\\*est](https://artiklid.elnet.ee/record=b2749536*est)